

Notice of References Cited	Application/Control No. 10/761,498	Applicant(s)/Patent Under Reexamination MICHON ET AL.	
	Examiner S. Devi, Ph.D.	Art Unit 1645	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Clemens et al. Ann. N Y Acad. Sci. 754: 255-266, 1995
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